

N THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: BIELLAK, STEVE; STOKOWSKI, STANLEY E.; VAEZ-IRAVANI, MEHDI
Assignee: KLA-TENCOR TECHNOLOGIES CORPORATION
Title: SYSTEM AND METHODS FOR A WAFER INSPECTION SYSTEM USING MULTIPLE ANGLES AND MULTIPLE WAVELENGTH ILLUMINATION
Serial No.: 09/891,693 Filing Date: June 26, 2001
Examiner: Hoa Q. Pham Group Art Unit: 2877
Docket No.: M-10693 US

San Francisco, California
February 27, 2003

BOX DAC
COMMISSIONER FOR PATENTS
Washington, DC 20231

RESPONSE TO OFFICE ACTION

RECEIVED

MAR 07 2003

OFFICE OF PETITIONS

Dear Sir:

This responds to the Office Action mailed on January 24, 2002, setting a period for response expiring on April 24, 2002. A Petition for Extension of Time to extend the response period to expire on July 24, 2002, was submitted together with this response on July 24, 2002. However, the application serial number was incorrectly entered on the Response documents as 09/298,007, thus, resulting in this Petition To Revive.

IN THE SPECIFICATION

On page 9, paragraph 33, line 5, please add after "channel 420." the following: -- In other words, illumination channel 416 is at around zero degrees to a normal direction to surface 426. -- The fully amended paragraph is attached hereto.

03/07/2003 RMDHDAF1 00000000 09891693

03 FC:1201
04 FC:1202
05 FC:1451

252.00 OP
648.00 OP
16.00 CP